



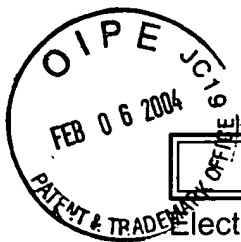
Electronic Filing System (EFS) Data
Electronic Patent Application Submission
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EFS ID: 55042
Application ID: 10688503
Title of Invention: SYSTEMS AND METHODS FOR
MULTI-DIMENSIONAL
METROLOGY AND/OR
INSPECTION OF A SPECIMEN
First Named Inventor: Tim Wihl
Domestic/Foreign Application: Domestic Application
Filing Date: 2003-10-17
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Statement
Filing Type:
Confirmation number: 1964
Attorney Docket Number: 5589-04301



Total Fees Authorized:


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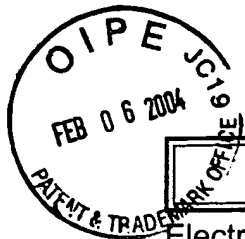


TRANSMITTAL

Electronic Version v1.1

Stylesheet Version v1.1.0

Title of Invention	SYSTEMS AND METHODS FOR MULTI-DIMENSIONAL METROLOGY AND/OR INSPECTION OF A SPECIMEN									
Application Number: 10/688503 										
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<table border="1"><thead><tr><th>Submitted by:</th><th>Elec. Sign.</th><th>Sign. Capacity</th></tr></thead><tbody><tr><td>Kevin L. Daffer Registered Number: 34146</td><td>Kevin L. Daffer</td><td>Attorney</td></tr></tbody></table>			Submitted by:	Elec. Sign.	Sign. Capacity	Kevin L. Daffer Registered Number: 34146	Kevin L. Daffer	Attorney		
Submitted by:	Elec. Sign.	Sign. Capacity								
Kevin L. Daffer Registered Number: 34146	Kevin L. Daffer	Attorney								
<table><tr><td>Documents being submitted</td><td>Files</td></tr><tr><td>us-ids</td><td>558904301IDS-usidst.xml</td></tr><tr><td></td><td>us-ids.dtd</td></tr><tr><td></td><td>us-ids.xsl</td></tr></table>			Documents being submitted	Files	us-ids	558904301IDS-usidst.xml		us-ids.dtd		us-ids.xsl
Documents being submitted	Files									
us-ids	558904301IDS-usidst.xml									
	us-ids.dtd									
	us-ids.xsl									
Comments										



ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

Title of
Invention

SYSTEMS AND METHODS FOR MULTI-DIMENSIONAL
METROLOGY AND/OR INSPECTION OF A SPECIMEN

Application Number: 10/688503



Confirmation Number: 1964

First Named Applicant: Tim Wihl

Attorney Docket Number: 5589-04301

Search string: (5999266 or 6181472 or 6268923 or
20020018118).pn.

US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
	1	5999266	1999-12-07	Takahashi et al.			
	2	6181472	2001-01-30	Liu			
	3	6268923	2001-07-31	Michniewicz et al.			

US Published Applications

Note: Applicant is not required to submit a paper copy of cited US Published Applications

init	Cite.No.	Pub. No.	Date	Applicant	Kind	Class	Subclass
	1	20020018118	2002-02-14	Coulombe et al.			

Signature

Examiner Name	Date